PATENT APPLICATION

00862.022246

APR 3 0 2003

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

În re Application of:	) : Examiner: H. Nguyen
Kazunori IWAMOTO et al.	)
Application No.: 09/866,600	: Group Art Unit: 2851 )
Filed: May 30, 2001	: )
For: STAGE APPARATUS WHICH SUPPORTS INTERFEROMETER, STAGE POSITION MEASUREMENT METHOD, PROJECTION EXPOSURE APPARATUS, PROJECTION EXPOSURE MAINTENANCE METHOD, SEMICONDUCTOR DEVICE MANUFACTURING METHOD, AND SEMICONDUCTOR MANUFACTURING FACTORY	April 30, 2003
Commissioner for Patents Washington, D.C. 20231	
Sir:	
Transmitted herewith is an Amendment in the above-identified application.	
X No additional fee is required.	

The fee has been calculated as shown below:

			CLAIMS AS AME	ENDED		
	CLAIMS REMAINING AFTER AMENDMENT		HIGHEST NO. PREVIOUSLY PAID FOR	PRESENT EXTRA	RATE	ADDITIONAL FEE
TOTAL CLAIMS	30	MINUS	30	= 0	x \$9 \$18	\$0.00
INDEP. CLAIMS	5	MINUS	5	= 0	x \$42 \$84	\$0.00
Fee for Multi	ple Dependent claims	\$140/\$280				
			TOTAL ADDITIO			\$0.00

	°Verified Statement claiming small entity status is enclosed, if not filed previously.			
	A check in the amount of \$ is enclosed including the additional claims fees.			
	Charge \$ to Deposit Account No. 06-1205. A duplicate of this sheet is enclosed.			
X	Any prior general authorization to charge an issue fee under 37 CFR 1.18 to Deposit Account No. 06-1205 is hereby revoked. The Commissioner is hereby authorized to charge any additional fees under 37 CFR 1.16 and 1.17 which may be required during the entire pendency of this application, or to credit any overpayment, to Deposit Account No. 06-1205. A duplicate of this paper is enclosed.			
	A check in the amount of \$ to cover the fee for a two month extension is enclosed.			
	A check in the amount of \$ to cover the Information Disclosure Statement fee is enclosed.			
X	Applicants' undersigned attorney may be reached in our Washington, D.C. office by telephone at (202) 530-1010. All correspondence should be directed to our address given below.			
	Respectfully submitted,			
	Attorney for Applicants Steven E. Warner Registration No. 33,326			

FITZPATRICK, CELLA, HARPER & SCINTO 30 Rockefeller Plaza
New York, New York 10112-3801
Facsimile: (212) 218-2200
SEW/eab

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Kazunori IWAMOTO et al.	)	
	:	Group Art Unit: 2851
Application No.: 09/866,600	)	
	:	
Filed: May 30, 2001	)	
	:	
For: STAGE APPARATUS WHICH SUPPORTS	)	April 30, 2003
INTERFEROMETER, STAGE POSITION	:	
MEASUREMENT METHOD, PROJECTION	)	
EXPOSURE APPARATUS, PROJECTION	:	
EXPOSURE APPARATUS MAINTENANCE	)	
METHOD, SEMICONDUCTOR DEVICE	:	
MANUFACTURING METHOD, AND	)	
SEMICONDUCTOR MANUFACTURING FACTORY	<i>"</i> :	
Commission of fee Potents		
Commissioner for Patents		
Washington, D.C. 20231		

## REQUEST FOR APPROVAL OF DRAWING CHANGES

Sir:

Applicants request that the Examiner approve the changes to Figures 5 and 6, as shown in red on the attached sketches, enclosed in duplicate.

In Figure 5, under "FIG. 5," insert -- PRIOR ART --, as shown.

In Figure 6, under "FIG. 6," insert -- PRIOR ART --, as shown.

Favorable consideration is requested.

Applicants' undersigned attorney may be reached in our Washington, D.C. office by telephone at (202) 530-1010 All correspondence should continue to be directed to our address given below.

Respectfully submitted,

Attorney for Applicants

Steven E. Warner

Registration No. 33,326

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